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MEMC 98-1451/2554.1 PATENT

Art Unit 1775

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of Robert J. Falster et al. Serial No. 10/073,506

Filed February 11, 2002 Confirmation No. 6190

For THERMAL ANNEALING PROCESS FOR PRODUCING LOW DEFECT

DENSITY SINGLE CRYSTAL SILICON

Examiner Matthew A. Anderson

November 19, 2003

## **AMENDMENT C**

TO THE COMMISSIONER FOR PATENTS,

SIR:

This amendment is in response to the Office action mailed August 19, 2003.

Amendments to the Claims are reflected in the listing of claims which begins on page 2.

Remarks begin on page 12.

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